



Calibration Laboratory of Schmid & Partner Engineering AG



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Accreditation No.: SCS 108

Client Sporton (Auden)

Certificate No: ET3-1787_May10

CALIBRATION CERTIFICATE

Object: ET3DV6 - SN:1787
Calibration procedure(s): QA CAL-01.v6, QA CAL-23.v3 and QA CAL-25.v2
Calibration date: May 18, 2010

This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI). The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)°C and humidity < 70%.

Calibration Equipment used (M&TE critical for calibration)

Table with 4 columns: Primary Standards, ID #, Cal Date (Certificate No.), Scheduled Calibration. Lists various power meters, sensors, attenuators, and probes with their respective IDs and calibration dates.

Table with 4 columns: Secondary Standards, ID #, Check Date (in house), Scheduled Check. Lists RF generator and Network Analyzer with their IDs and check dates.

Calibrated by: Jeton Kastrali, Laboratory Technician
Approved by: Katja Pokovic, Technical Manager

Handwritten signatures of Jeton Kastrali and Katja Pokovic.

Issued: May 22, 2010

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Calibration Laboratory of
Schmid & Partner
Engineering AG
 Zeughausstrasse 43, 8004 Zurich, Switzerland



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Accreditation No.: **SCS 108**

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Glossary:

TSL	tissue simulating liquid
NORM _{x,y,z}	sensitivity in free space
ConvF	sensitivity in TSL / NORM _{x,y,z}
DCP	diode compression point
CF	crest factor (1/duty_cycle) of the RF signal
A, B, C	modulation dependent linearization parameters
Polarization φ	φ rotation around probe axis
Polarization ϑ	ϑ rotation around an axis that is in the plane normal to probe axis (at measurement center), i.e., $\vartheta = 0$ is normal to probe axis

Calibration is Performed According to the Following Standards:

- IEEE Std 1528-2003, "IEEE Recommended Practice for Determining the Peak Spatial-Averaged Specific Absorption Rate (SAR) in the Human Head from Wireless Communications Devices: Measurement Techniques", December 2003
- IEC 62209-1, "Procedure to measure the Specific Absorption Rate (SAR) for hand-held devices used in close proximity to the ear (frequency range of 300 MHz to 3 GHz)", February 2005

Methods Applied and Interpretation of Parameters:

- NORM_{x,y,z}**: Assessed for E-field polarization $\vartheta = 0$ ($f \leq 900$ MHz in TEM-cell; $f > 1800$ MHz: R22 waveguide). NORM_{x,y,z} are only intermediate values, i.e., the uncertainties of NORM_{x,y,z} does not effect the E²-field uncertainty inside TSL (see below *ConvF*).
- NORM(f)_{x,y,z}** = NORM_{x,y,z} * *frequency_response* (see Frequency Response Chart). This linearization is implemented in DAS Y4 software versions later than 4.2. The uncertainty of the frequency response is included in the stated uncertainty of *ConvF*.
- DCP_{x,y,z}**: DCP are numerical linearization parameters assessed based on the data of power sweep with CW signal (no uncertainty required). DCP does not depend on frequency nor media.
- A_{x,y,z}; B_{x,y,z}; C_{x,y,z}; VR_{x,y,z}**: A, B, C are numerical linearization parameters assessed based on the data of power sweep for specific modulation signal. The parameters do not depend on frequency nor media. VR is the maximum calibration range expressed in RMS voltage across the diode.
- ConvF and Boundary Effect Parameters**: Assessed in flat phantom using E-field (or Temperature Transfer Standard for $f \leq 800$ MHz) and inside waveguide using analytical field distributions based on power measurements for $f > 800$ MHz. The same setups are used for assessment of the parameters applied for boundary compensation (alpha, depth) of which typical uncertainty values are given. These parameters are used in DAS Y4 software to improve probe accuracy close to the boundary. The sensitivity in TSL corresponds to NORM_{x,y,z} * *ConvF* whereby the uncertainty corresponds to that given for *ConvF*. A frequency dependent *ConvF* is used in DAS Y version 4.4 and higher which allows extending the validity from ± 50 MHz to ± 100 MHz.
- Spherical isotropy (3D deviation from isotropy)**: in a field of low gradients realized using a flat phantom exposed by a patch antenna.
- Sensor Offset**: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.



ET3DV6 SN:1787

May 18, 2010

Probe ET3DV6

SN:1787

Manufactured:	May 28, 2003
Last calibrated:	May 26, 2009
Recalibrated:	May 18, 2010

Calibrated for DAS Y/EASY Systems

(Note: non-compatible with DAS Y2 system!)



ET3DV6 SN:1787

May 18, 2010

DASY/EASY - Parameters of Probe: ET3DV6 SN:1787

Basic Calibration Parameters

	Sensor X	Sensor Y	Sensor Z	Unc (k=2)
Norm ($\mu\text{V}/(\text{V}/\text{m})^2$) ^A	1.60	1.79	2.10	$\pm 10.1\%$
DCP (mV) ^B	92.4	95.5	91.0	

Modulation Calibration Parameters

UID	Communication System Name	PAR		A dB	B dBuV	C	VR mV	Unc ^E (k=2)
10000	CW	0.00	X	0.00	0.00	1.00	300.0	$\pm 1.5\%$
			Y	0.00	0.00	1.00	300.0	
			Z	0.00	0.00	1.00	300.0	

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor $k=2$, which for a normal distribution corresponds to a coverage probability of approximately 95%.

^A The uncertainties of NormX,Y,Z do not affect the E^2 -field uncertainty inside TSL (see Pages 5 and 6).

^B Numerical linearization parameter: uncertainty not required.

^E Uncertainty is determined using the maximum deviation from linear response applying rectangular distribution and is expressed for the square of the field value.



ET3DV6 SN:1787

May 18, 2010

DASY/EASY - Parameters of Probe: ET3DV6 SN:1787

Calibration Parameter Determined in Head Tissue Simulating Media

f [MHz]	Validity [MHz] [□]	Permittivity	Conductivity	ConvF X	ConvF Y	ConvF Z	Alpha	Depth Unc (k=2)
750	± 50 / ± 100	41.5 ± 5%	0.90 ± 5%	6.56	6.56	6.56	0.52	1.96 ± 11.0%
835	± 50 / ± 100	41.9 ± 5%	0.89 ± 5%	6.21	6.21	6.21	0.42	2.23 ± 11.0%
1750	± 50 / ± 100	40.1 ± 5%	1.37 ± 5%	5.36	5.36	5.36	0.49	1.18 ± 11.0%
1900	± 50 / ± 100	40.0 ± 5%	1.40 ± 5%	5.09	5.09	5.09	0.66	2.20 ± 11.0%
2450	± 50 / ± 100	39.2 ± 5%	1.80 ± 5%	4.50	4.50	4.50	0.99	1.63 ± 11.0%

[□] The validity of ± 100 MHz only applies for DASY v4.4 and higher (see Page 2). The uncertainty is the RSS of the ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band.



ET3DV6 SN:1787

May 18, 2010

DASY/EASY - Parameters of Probe: ET3DV6 SN:1787

Calibration Parameter Determined in Body Tissue Simulating Media

f [MHz]	Validity [MHz] ^c	Permittivity	Conductivity	ConvF X	ConvF Y	ConvF Z	Alpha	Depth Unc (k=2)
750	± 50 / ± 100	55.5 ± 5%	0.96 ± 5%	6.22	6.22	6.22	0.48	2.20 ± 11.0%
835	± 50 / ± 100	55.2 ± 5%	0.97 ± 5%	6.12	6.12	6.12	0.39	2.45 ± 11.0%
1750	± 50 / ± 100	53.4 ± 5%	1.49 ± 5%	4.72	4.72	4.72	0.63	2.90 ± 11.0%
1900	± 50 / ± 100	53.3 ± 5%	1.52 ± 5%	4.47	4.47	4.47	0.88	2.39 ± 11.0%
2450	± 50 / ± 100	52.7 ± 5%	1.95 ± 5%	4.03	4.03	4.03	0.99	1.35 ± 11.0%

^c The validity of ± 100 MHz only applies for DASY v4.4 and higher (see Page 2). The uncertainty is the RSS of the ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band.

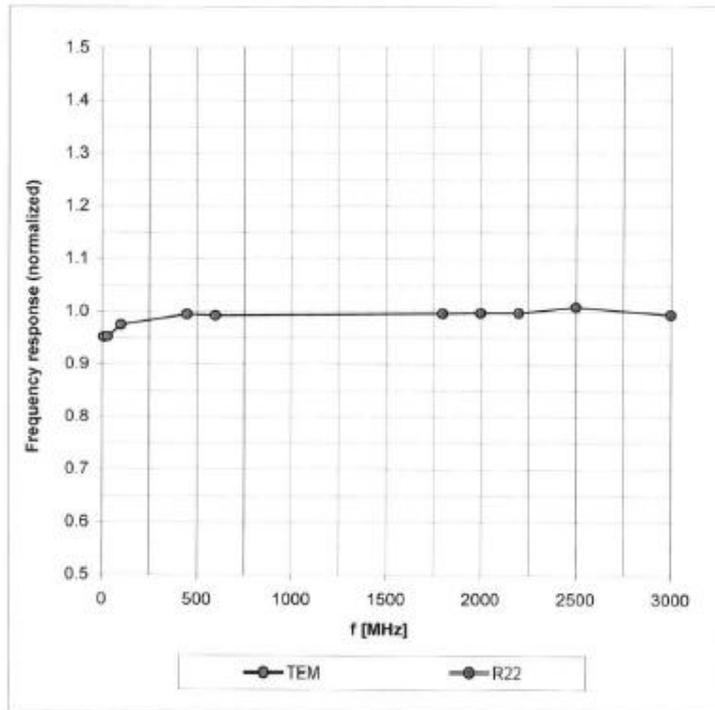


ET3DV6 SN:1787

May 18, 2010

Frequency Response of E-Field

(TEM-Cell:ifi110 EXX, Waveguide: R22)



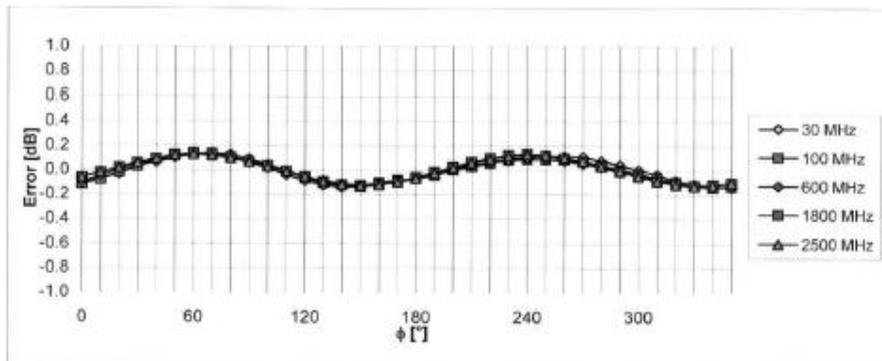
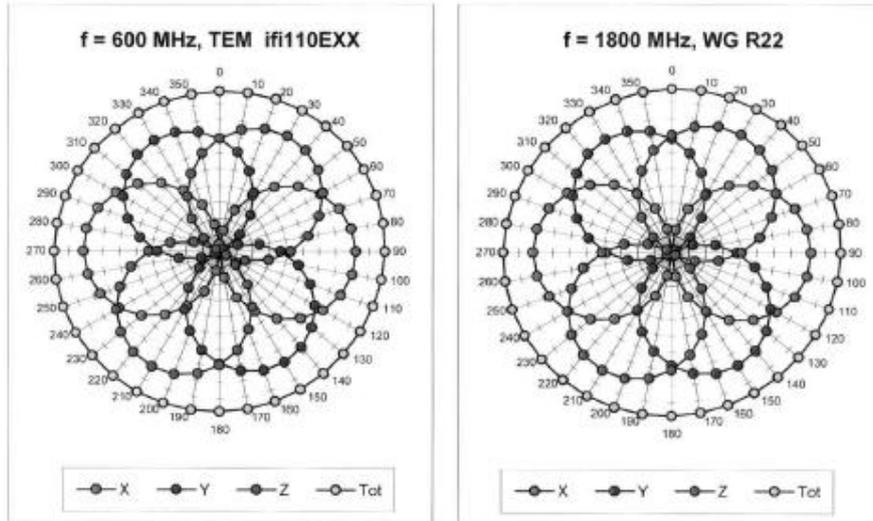
Uncertainty of Frequency Response of E-field: $\pm 6.3\%$ (k=2)



ET3DV6 SN:1787

May 18, 2010

Receiving Pattern (ϕ), $\vartheta = 0^\circ$



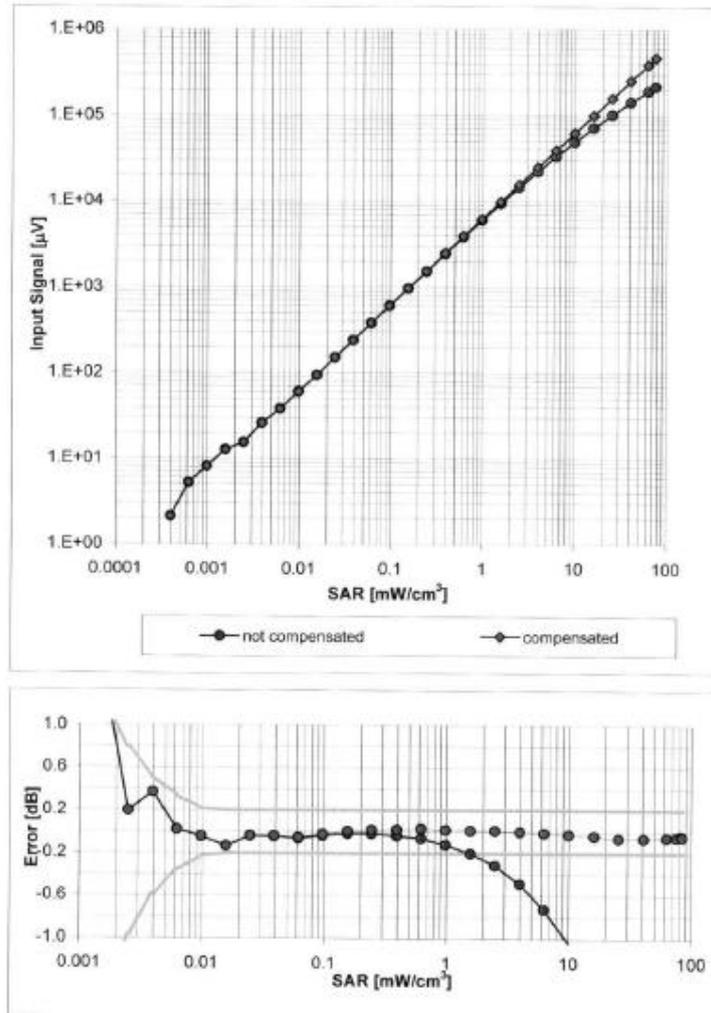
Uncertainty of Axial Isotropy Assessment: $\pm 0.5\%$ ($k=2$)



ET3DV6 SN:1787

May 18, 2010

Dynamic Range f(SAR_{head}) (Waveguide R22, f = 1800 MHz)

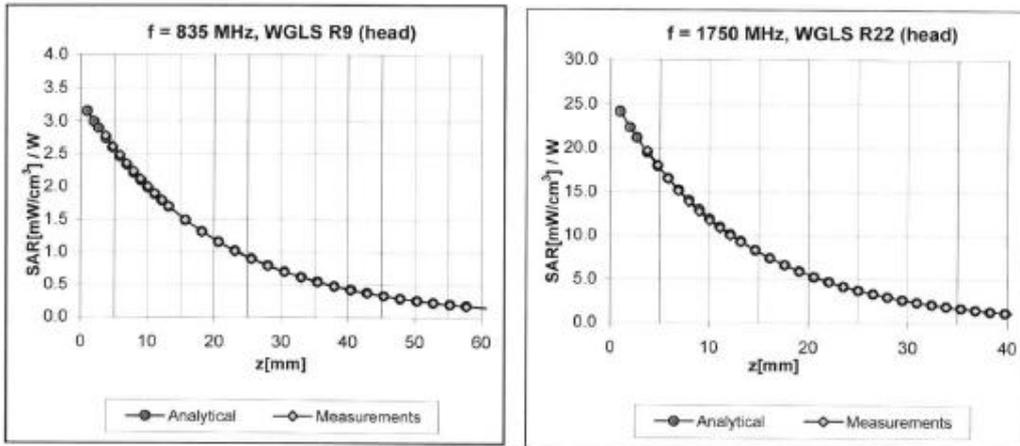


Uncertainty of Linearity Assessment: ± 0.6% (k=2)

ET3DV6 SN:1787

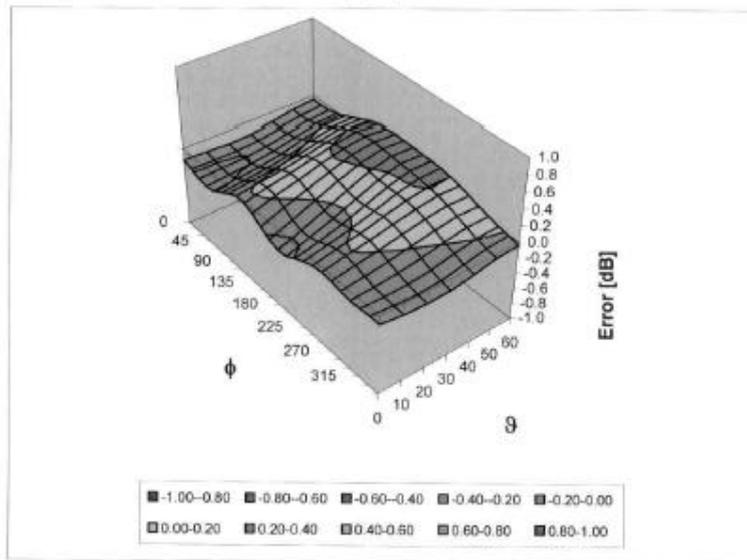
May 18, 2010

Conversion Factor Assessment



Deviation from Isotropy in HSL

Error (ϕ , θ), f = 900 MHz



Uncertainty of Spherical Isotropy Assessment: $\pm 2.6\%$ (k=2)



ET3DV6 SN:1787

May 18, 2010

Other Probe Parameters

Sensor Arrangement	Triangular
Connector Angle (°)	Not applicable
Mechanical Surface Detection Mode	enabled
Optical Surface Detection Mode	disabled
Probe Overall Length	337 mm
Probe Body Diameter	10 mm
Tip Length	10 mm
Tip Diameter	6.8 mm
Probe Tip to Sensor X Calibration Point	2.7 mm
Probe Tip to Sensor Y Calibration Point	2.7 mm
Probe Tip to Sensor Z Calibration Point	2.7 mm
Recommended Measurement Distance from Surface	4 mm



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Accreditation No.: SCS 108

Client Sporton (Auden)

Certificate No: ET3-1788_Sep10

CALIBRATION CERTIFICATE

Object: ET3DV6 - SN:1788
Calibration procedure(s): QA CAL-01.v6, QA CAL-23.v3 and QA CAL-25.v2
Calibration procedure for dosimetric E-field probes
Calibration date: September 21, 2010

This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI). The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)°C and humidity < 70%.

Calibration Equipment used (M&TE critical for calibration)

Table with 4 columns: Primary Standards, ID #, Cal Date (Certificate No.), Scheduled Calibration. Lists equipment like Power meter E4419B, Reference 3 dB Attenuator, etc.

Table with 4 columns: Secondary Standards, ID #, Check Date (in house), Scheduled Check. Lists RF generator HP 8648C, Network Analyzer HP 8753E.

Calibrated by: Jeton Kastrati, Laboratory Technician
Approved by: Katja Pokovic, Technical Manager

Issued: September 22, 2010

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Accreditation No.: **SCS 108**

Glossary:

TSL	tissue simulating liquid
NORM _{x,y,z}	sensitivity in free space
ConvF	sensitivity in TSL / NORM _{x,y,z}
DCP	diode compression point
CF	crest factor (1/duty_cycle) of the RF signal
A, B, C	modulation dependent linearization parameters
Polarization φ	φ rotation around probe axis
Polarization ϑ	ϑ rotation around an axis that is in the plane normal to probe axis (at measurement center), i.e., $\vartheta = 0$ is normal to probe axis

Calibration is Performed According to the Following Standards:

- a) IEEE Std 1528-2003, "IEEE Recommended Practice for Determining the Peak Spatial-Averaged Specific Absorption Rate (SAR) in the Human Head from Wireless Communications Devices: Measurement Techniques", December 2003
- b) IEC 62209-1, "Procedure to measure the Specific Absorption Rate (SAR) for hand-held devices used in close proximity to the ear (frequency range of 300 MHz to 3 GHz)", February 2005

Methods Applied and Interpretation of Parameters:

- **NORM_{x,y,z}:** Assessed for E-field polarization $\vartheta = 0$ ($f \leq 900$ MHz in TEM-cell; $f > 1800$ MHz: R22 waveguide). NORM_{x,y,z} are only intermediate values, i.e., the uncertainties of NORM_{x,y,z} does not effect the E²-field uncertainty inside TSL (see below ConvF).
- **NORM(f)_{x,y,z} = NORM_{x,y,z} * frequency_response** (see Frequency Response Chart). This linearization is implemented in DAS Y4 software versions later than 4.2. The uncertainty of the frequency response is included in the stated uncertainty of ConvF.
- **DCP_{x,y,z}:** DCP are numerical linearization parameters assessed based on the data of power sweep with CW signal (no uncertainty required). DCP does not depend on frequency nor media.
- **A_{x,y,z}; B_{x,y,z}; C_{x,y,z}; VR_{x,y,z}:** A, B, C are numerical linearization parameters assessed based on the data of power sweep for specific modulation signal. The parameters do not depend on frequency nor media. VR is the maximum calibration range expressed in RMS voltage across the diode.
- **ConvF and Boundary Effect Parameters:** Assessed in flat phantom using E-field (or Temperature Transfer Standard for $f \leq 800$ MHz) and inside waveguide using analytical field distributions based on power measurements for $f > 800$ MHz. The same setups are used for assessment of the parameters applied for boundary compensation (alpha, depth) of which typical uncertainty values are given. These parameters are used in DAS Y4 software to improve probe accuracy close to the boundary. The sensitivity in TSL corresponds to NORM_{x,y,z} * ConvF whereby the uncertainty corresponds to that given for ConvF. A frequency dependent ConvF is used in DAS Y version 4.4 and higher which allows extending the validity from ± 50 MHz to ± 100 MHz.
- **Spherical isotropy (3D deviation from isotropy):** in a field of low gradients realized using a flat phantom exposed by a patch antenna.
- **Sensor Offset:** The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.



ET3DV6 SN:1788

September 21, 2010

Probe ET3DV6

SN:1788

Manufactured:	May 28, 2003
Last calibrated:	September 23, 2009
Recalibrated:	September 21, 2010

Calibrated for DASYS/EASY Systems

(Note: non-compatible with DASYS2 system!)



ET3DV6 SN:1788

September 21, 2010

DASY/EASY - Parameters of Probe: ET3DV6 SN:1788

Basic Calibration Parameters

	Sensor X	Sensor Y	Sensor Z	Unc (k=2)
Norm ($\mu\text{V}/(\text{V}/\text{m})^2$) ^A	1.76	1.69	1.76	$\pm 10.1\%$
DCP (mV) ^B	91.6	91.0	95.1	

Modulation Calibration Parameters

UID	Communication System Name	PAR		A dB	B dBuV	C	VR mV	Unc ^E (k=2)
10000	CW	0.00	X	0.00	0.00	1.00	300.0	$\pm 1.5\%$
			Y	0.00	0.00	1.00	300.0	
			Z	0.00	0.00	1.00	300.0	

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

^A The uncertainties of NormX,Y,Z do not affect the E²-field uncertainty inside TSL, (see Pages 5 and 6).

^B Numerical linearization parameter: uncertainty not required.

^E Uncertainty is determined using the maximum deviation from linear response applying rectangular distribution and is expressed for the square of the field value.



ET3DV6 SN:1788

September 21, 2010

DASY/EASY - Parameters of Probe: ET3DV6 SN:1788

Calibration Parameter Determined in Head Tissue Simulating Media

f [MHz]	Validity [MHz] ^c	Permittivity	Conductivity	ConvF X	ConvF Y	ConvF Z	Alpha	Depth Unc (k=2)
835	± 50 / ± 100	41.5 ± 5%	0.90 ± 5%	6.23	6.23	6.23	0.41	2.32 ± 11.0%
900	± 50 / ± 100	41.5 ± 5%	0.97 ± 5%	6.11	6.11	6.11	0.29	2.85 ± 11.0%
1750	± 50 / ± 100	40.1 ± 5%	1.37 ± 5%	5.29	5.29	5.29	0.51	2.51 ± 11.0%
1900	± 50 / ± 100	40.0 ± 5%	1.40 ± 5%	5.03	5.03	5.03	0.66	2.25 ± 11.0%
2450	± 50 / ± 100	39.2 ± 5%	1.80 ± 5%	4.35	4.35	4.35	0.99	1.69 ± 11.0%

^c The validity of ± 100 MHz only applies for DASY v4.4 and higher (see Page 2). The uncertainty is the RSS of the ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band.



ET3DV6 SN:1788

September 21, 2010

DASY/EASY - Parameters of Probe: ET3DV6 SN:1788

Calibration Parameter Determined in Body Tissue Simulating Media

f [MHz]	Validity [MHz] ^c	Permittivity	Conductivity	ConvF X	ConvF Y	ConvF Z	Alpha	Depth Unc (k=2)
835	± 50 / ± 100	55.2 ± 5%	0.97 ± 5%	5.99	5.99	5.99	0.35	2.62 ± 11.0%
900	± 50 / ± 100	55.0 ± 5%	1.05 ± 5%	6.07	6.07	6.07	0.32	2.87 ± 11.0%
1750	± 50 / ± 100	53.4 ± 5%	1.49 ± 5%	4.67	4.67	4.67	0.61	3.09 ± 11.0%
1900	± 50 / ± 100	53.3 ± 5%	1.52 ± 5%	4.39	4.39	4.39	0.83	2.56 ± 11.0%
2450	± 50 / ± 100	52.7 ± 5%	1.95 ± 5%	4.04	4.04	4.04	0.99	1.40 ± 11.0%

^c The validity of ± 100 MHz only applies for DASY v4.4 and higher (see Page 2). The uncertainty is the RSS of the ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band.

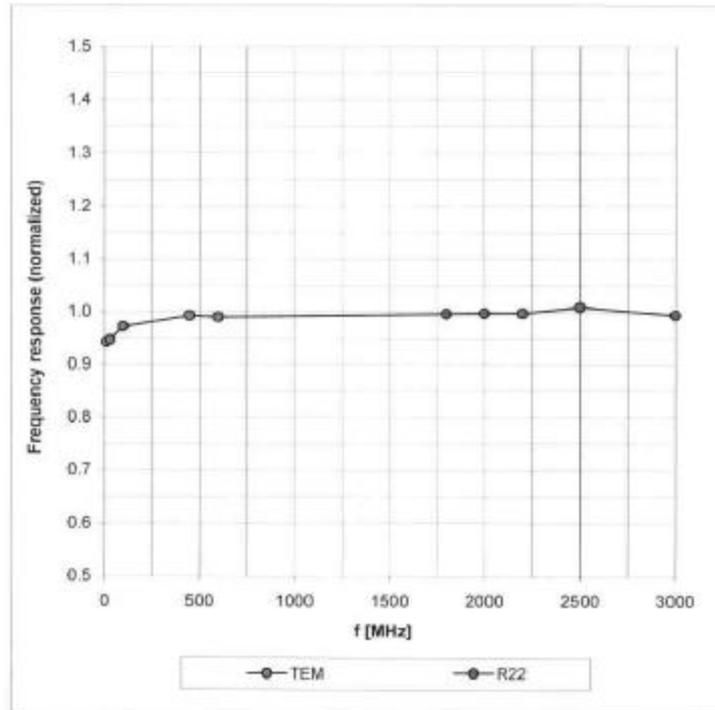


ET3DV6 SN:1788

September 21, 2010

Frequency Response of E-Field

(TEM-Cell:ifi110 EXX, Waveguide: R22)



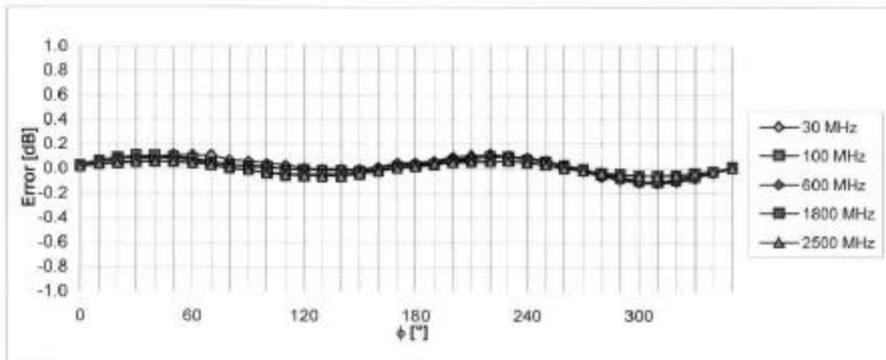
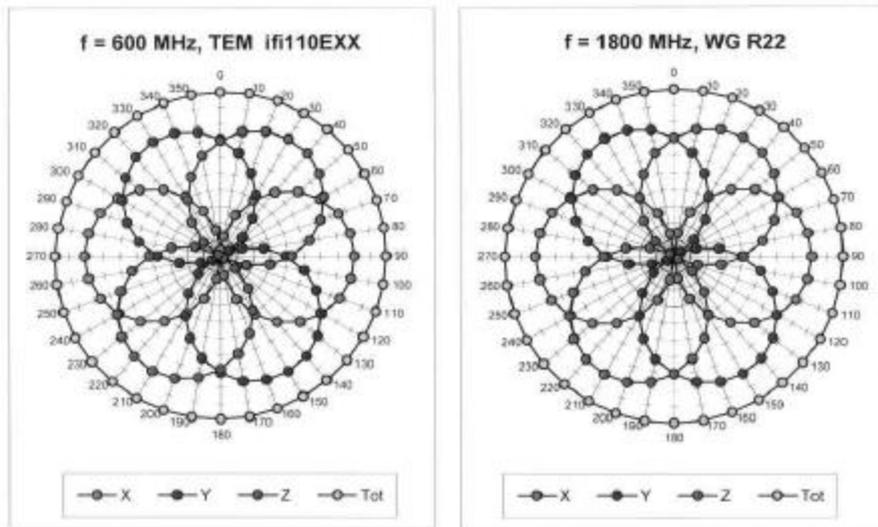
Uncertainty of Frequency Response of E-field: $\pm 6.3\%$ (k=2)



ET3DV6 SN:1788

September 21, 2010

Receiving Pattern (ϕ), $\theta = 0^\circ$



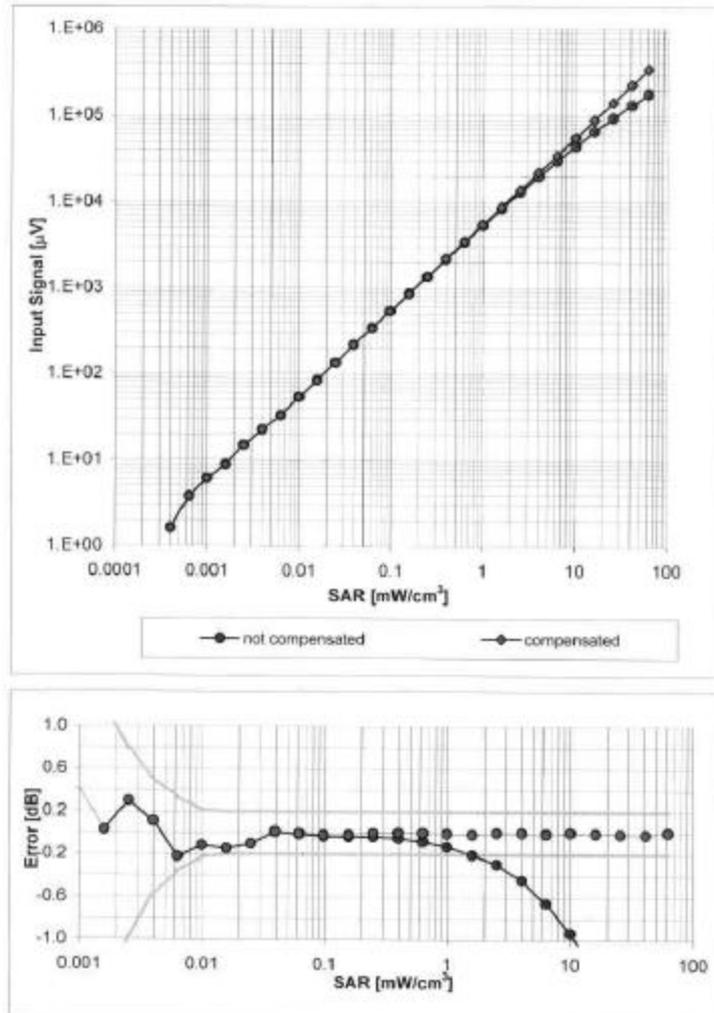
Uncertainty of Axial Isotropy Assessment: $\pm 0.5\%$ (k=2)



ET3DV6 SN:1788

September 21, 2010

Dynamic Range $f(SAR_{head})$ (Waveguide R22, $f = 1800$ MHz)

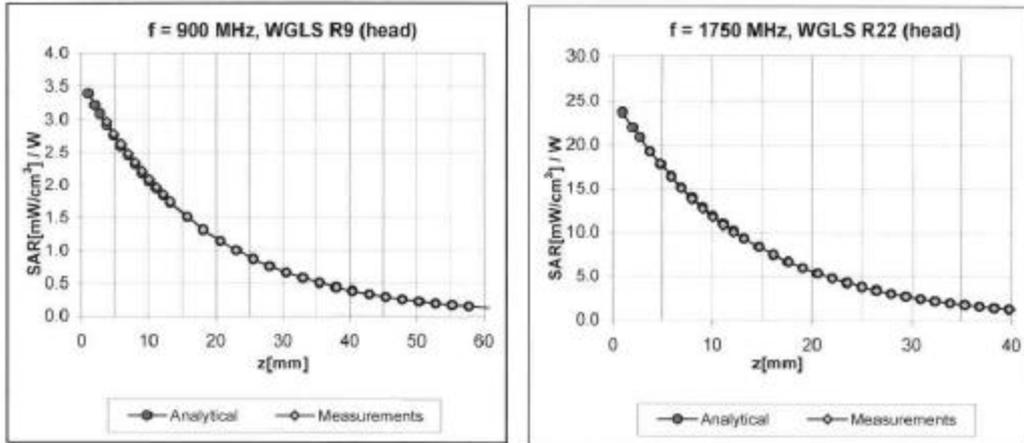


Uncertainty of Linearity Assessment: $\pm 0.6\%$ ($k=2$)

ET3DV6 SN:1788

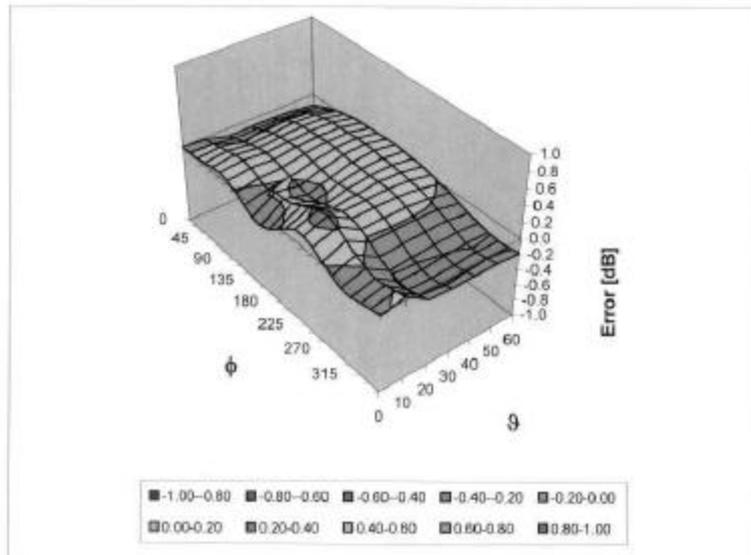
September 21, 2010

Conversion Factor Assessment



Deviation from Isotropy in HSL

Error (ϕ, θ), f = 900 MHz



Uncertainty of Spherical Isotropy Assessment: $\pm 2.6\%$ (k=2)



ET3DV6 SN:1788

September 21, 2010

Other Probe Parameters

Sensor Arrangement	Triangular
Connector Angle (°)	Not applicable
Mechanical Surface Detection Mode	enabled
Optical Surface Detection Mode	disabled
Probe Overall Length	337 mm
Probe Body Diameter	10 mm
Tip Length	10 mm
Tip Diameter	6.8 mm
Probe Tip to Sensor X Calibration Point	2.7 mm
Probe Tip to Sensor Y Calibration Point	2.7 mm
Probe Tip to Sensor Z Calibration Point	2.7 mm
Recommended Measurement Distance from Surface	4 mm



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Accreditation No.: SCS 108

Client Auden

Certificate No: EX3-3661_Dec09

CALIBRATION CERTIFICATE
Object: EX3DV4 - SN:3661
Calibration procedure(s): QA CAL-01.v6, QA CAL-14.v3, QA CAL-23.v3 and QA CAL-25.v2
Calibration date: December 30, 2009
This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI).
All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)°C and humidity < 70%.
Calibration Equipment used (M&TE critical for calibration)
Primary Standards table with columns: Primary Standards, ID #, Cal Date (Certificate No.), Scheduled Calibration.
Secondary Standards table with columns: Secondary Standards, ID #, Check Date (in house), Scheduled Check.
Calibrated by: Katja Pokovic, Technical Manager
Approved by: Niels Kuster, Quality Manager
Signature of Niels Kuster
Issued: December 30, 2009
This calibration certificate shall not be reproduced except in full without written approval of the laboratory.

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- **NORM(f)_{x,y,z}** = NORM_{x,y,z} * *frequency_response* (see Frequency Response Chart). This linearization is implemented in DAS Y4 software versions later than 4.2. The uncertainty of the frequency response is included in the stated uncertainty of *ConvF*.
- **DCP_{x,y,z}**: DCP are numerical linearization parameters assessed based on the data of power sweep with CW signal (no uncertainty required). DCP does not depend on frequency nor media.
- **A_{x,y,z}; B_{x,y,z}; C_{x,y,z}; VR_{x,y,z}; A, B, C** are numerical linearization parameters assessed based on the data of power sweep for specific modulation signal. The parameters do not depend on frequency nor media. VR is the maximum calibration range expressed in RMS voltage across the diode.
- **ConvF and Boundary Effect Parameters**: Assessed in flat phantom using E-field (or Temperature Transfer Standard for $f \leq 800$ MHz) and inside waveguide using analytical field distributions based on power measurements for $f > 800$ MHz. The same setups are used for assessment of the parameters applied for boundary compensation (alpha, depth) of which typical uncertainty values are given. These parameters are used in DAS Y4 software to improve probe accuracy close to the boundary. The sensitivity in TSL corresponds to NORM_{x,y,z} * *ConvF* whereby the uncertainty corresponds to that given for *ConvF*. A frequency dependent *ConvF* is used in DAS Y version 4.4 and higher which allows extending the validity from ± 50 MHz to ± 100 MHz.
- **Spherical isotropy (3D deviation from isotropy)**: in a field of low gradients realized using a flat phantom exposed by a patch antenna.
- **Sensor Offset**: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.



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Probe EX3DV4

SN:3661

Manufactured:	October 20, 2008
Calibrated:	December 30, 2009

Calibrated for DASY Systems

(Note: non-compatible with DASY2 system!)



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DASY - Parameters of Probe: EX3DV4 SN:3661

Basic Calibration Parameters

	Sensor X	Sensor Y	Sensor Z	Unc (k=2)
Norm ($\mu\text{V}/(\text{V}/\text{m})^2$) ^A	0.46	0.52	0.48	$\pm 10.1\%$
DCP (mV) ^B	89.4	91.4	90.5	

Modulation Calibration Parameters

UID	Communication System Name	PAR		A dB	B dBuV	C	VR mV	Unc ^E (k=2)
10000	CW	0.00	X	0.00	0.00	1.00	300	$\pm 1.5\%$
			Y	0.00	0.00	1.00	300	
			Z	0.00	0.00	1.00	300	

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

^A The uncertainties of NormX,Y,Z do not affect the E²-field uncertainty inside TSL (see Pages 5 and 6).

^B Numerical linearization parameter: uncertainty not required.

^E Uncertainty is determined using the maximum deviation from linear response applying rectangular distribution and is expressed for the square of the field value.



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DASY - Parameters of Probe: EX3DV4 SN:3661

Calibration Parameter Determined in Head Tissue Simulating Media

f [MHz]	Validity [MHz] ^c	Permittivity	Conductivity	ConvF X	ConvF Y	ConvF Z	Alpha	Depth Unc (k=2)
835	± 50 / ± 100	41.5 ± 5%	0.90 ± 5%	9.34	9.34	9.34	0.69	0.64 ± 11.0%
900	± 50 / ± 100	41.5 ± 5%	0.97 ± 5%	9.06	9.06	9.06	0.72	0.64 ± 11.0%
1750	± 50 / ± 100	40.1 ± 5%	1.37 ± 5%	8.19	8.19	8.19	0.59	0.63 ± 11.0%
1950	± 50 / ± 100	40.0 ± 5%	1.40 ± 5%	7.77	7.77	7.77	0.83	0.56 ± 11.0%
2450	± 50 / ± 100	39.2 ± 5%	1.80 ± 5%	7.22	7.22	7.22	0.35	0.83 ± 11.0%
5200	± 50 / ± 100	36.0 ± 5%	4.66 ± 5%	5.01	5.01	5.01	0.45	1.75 ± 13.1%
5500	± 50 / ± 100	35.6 ± 5%	4.96 ± 5%	4.38	4.38	4.38	0.48	1.75 ± 13.1%
5800	± 50 / ± 100	35.3 ± 5%	5.27 ± 5%	4.26	4.26	4.26	0.45	1.75 ± 13.1%

^c The validity of ± 100 MHz only applies for DASY v4.4 and higher (see Page 2). The uncertainty is the RSS of the ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band.



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DASY - Parameters of Probe: EX3DV4 SN:3661

Calibration Parameter Determined in Body Tissue Simulating Media

f [MHz]	Validity [MHz] ^c	Permittivity	Conductivity	ConvF X	ConvF Y	ConvF Z	Alpha	Depth Unc (k=2)
835	± 50 / ± 100	55.2 ± 5%	0.97 ± 5%	9.24	9.24	9.24	0.54	0.73 ± 11.0%
900	± 50 / ± 100	55.0 ± 5%	1.05 ± 5%	8.97	8.97	8.97	0.53	0.72 ± 11.0%
1750	± 50 / ± 100	53.4 ± 5%	1.49 ± 5%	7.93	7.93	7.93	0.67	0.65 ± 11.0%
1950	± 50 / ± 100	53.3 ± 5%	1.52 ± 5%	7.60	7.60	7.60	0.60	0.69 ± 11.0%
2450	± 50 / ± 100	52.7 ± 5%	1.95 ± 5%	7.34	7.34	7.34	0.26	1.12 ± 11.0%
5200	± 50 / ± 100	49.0 ± 5%	5.30 ± 5%	4.59	4.59	4.59	0.46	1.75 ± 13.1%
5500	± 50 / ± 100	48.6 ± 5%	5.65 ± 5%	4.11	4.11	4.11	0.46	1.75 ± 13.1%
5800	± 50 / ± 100	48.2 ± 5%	6.00 ± 5%	4.12	4.12	4.12	0.48	1.75 ± 13.1%

^c The validity of ± 100 MHz only applies for DAS Y v4.4 and higher (see Page 2). The uncertainty is the RSS of the ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band.

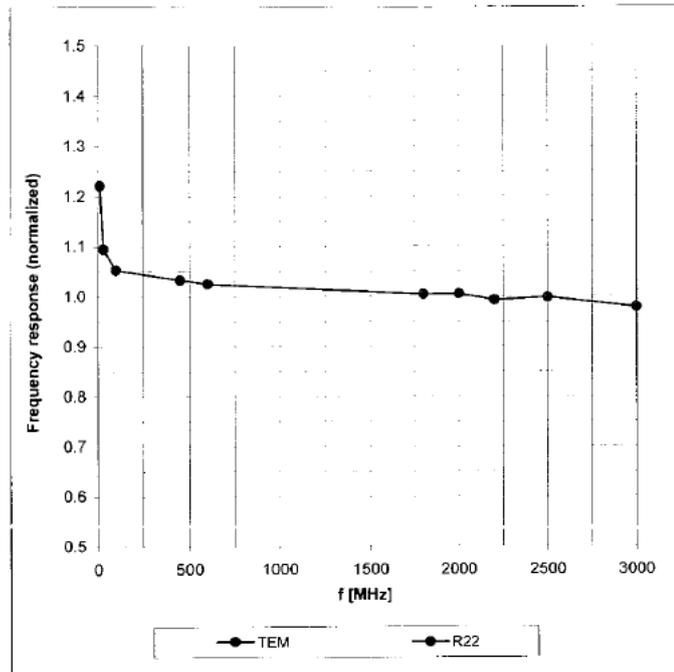


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Frequency Response of E-Field

(TEM-Cell: ifi110 EXX, Waveguide: R22)



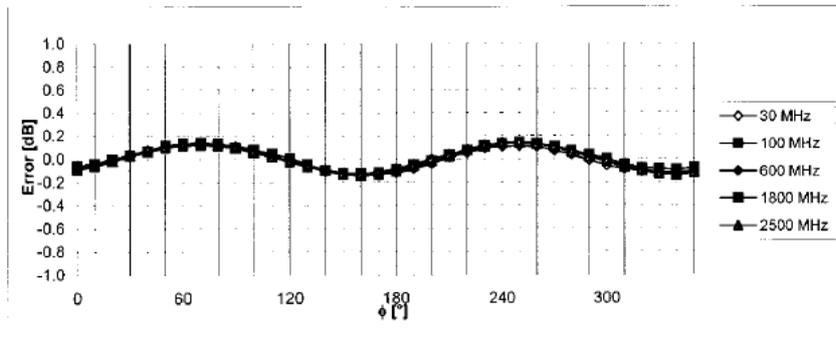
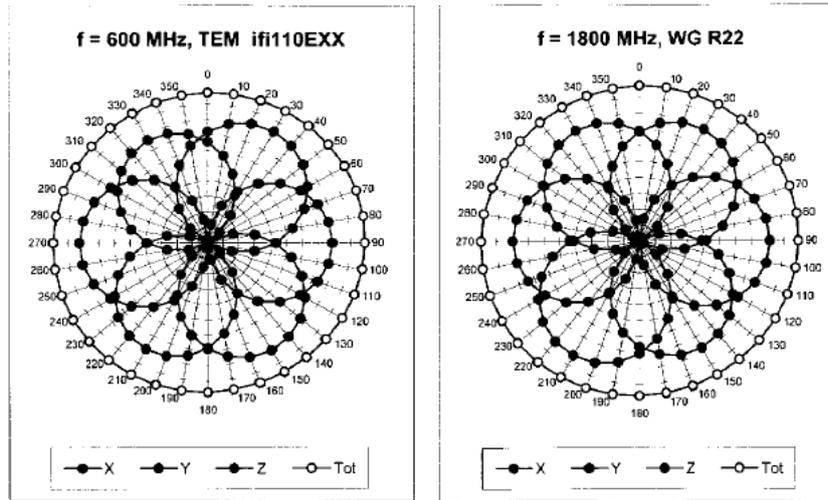
Uncertainty of Frequency Response of E-field: $\pm 6.3\%$ (k=2)



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Receiving Pattern (ϕ), $\theta = 0^\circ$



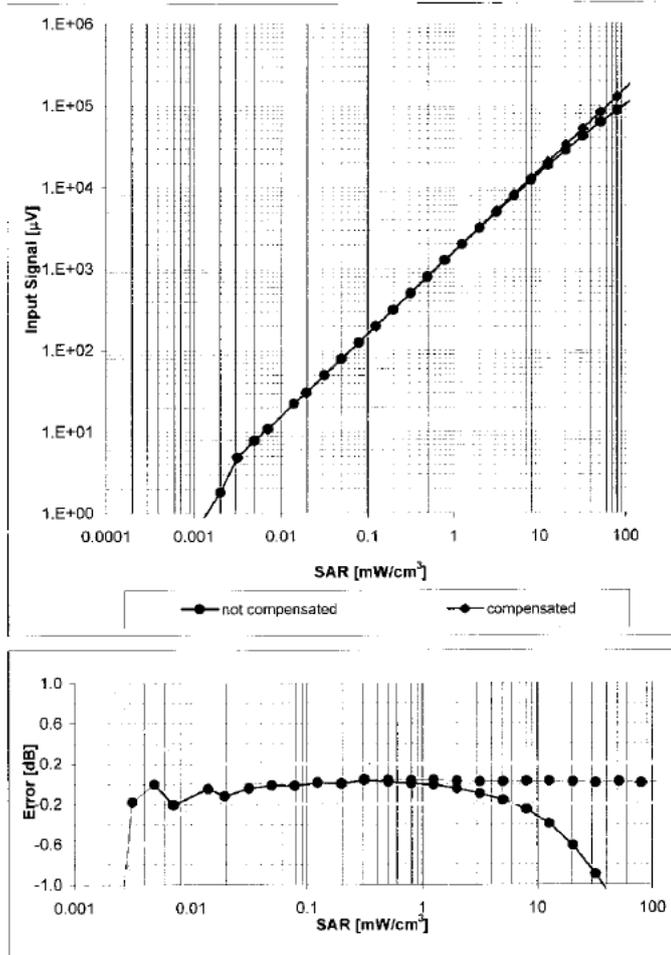
Uncertainty of Axial Isotropy Assessment: $\pm 0.5\%$ (k=2)



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Dynamic Range $f(SAR_{head})$ (Waveguide R22, $f = 1800$ MHz)

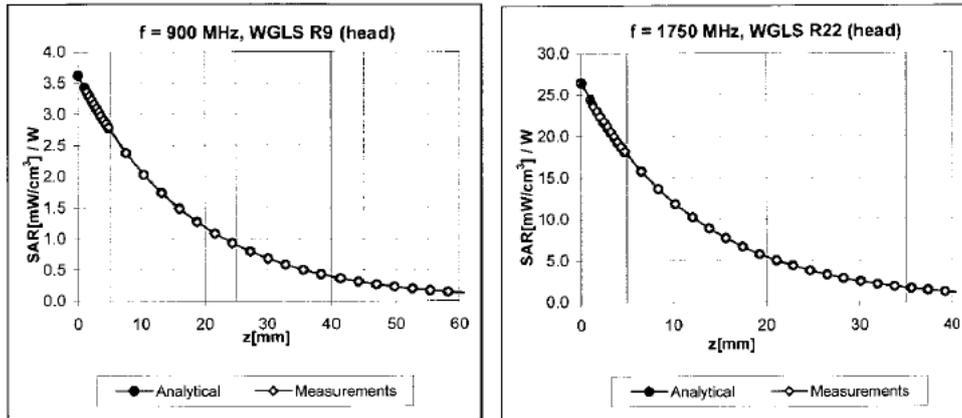


Uncertainty of Linearity Assessment: $\pm 0.6\%$ ($k=2$)

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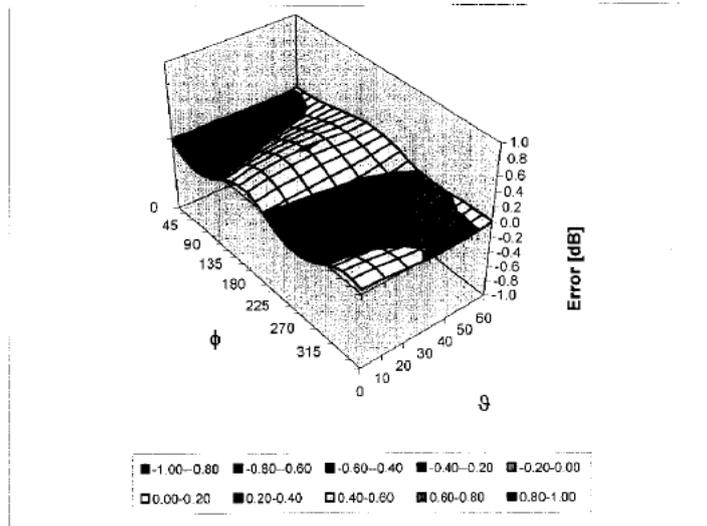
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Conversion Factor Assessment



Deviation from Isotropy in HSL

Error (ϕ, θ), f = 900 MHz



Uncertainty of Spherical Isotropy Assessment: $\pm 2.6\%$ (k=2)



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Other Probe Parameters

Sensor Arrangement	Triangular
Connector Angle (°)	Not applicable
Mechanical Surface Detection Mode	enabled
Optical Surface Detection Mode	disabled
Probe Overall Length	337 mm
Probe Body Diameter	10 mm
Tip Length	9 mm
Tip Diameter	2.5 mm
Probe Tip to Sensor X Calibration Point	1 mm
Probe Tip to Sensor Y Calibration Point	1 mm
Probe Tip to Sensor Z Calibration Point	1 mm
Recommended Measurement Distance from Surface	2 mm